

Search Notes

Application/Control No.

10/644,755

Examiner

Anthony Weier

Applicant(s)/Patent under
Reexamination

LORTZ ET AL.

Art Unit

1761

SEARCHED

| Class | Subclass | Date | Examiner |
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| 426 | 422 | 11/22/2006 | AW |
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INTERFERENCE SEARCHED

| Class | Subclass | Date | Examiner |
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**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

| | DATE | EXMR |
|-----------------|------------|------|
| Inventor Search | 11/22/2006 | AW |
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